

<b>Notice of References Cited</b>	Application/Control No. 10/602,387	Applicant(s)/Patent Under Reexamination BHATIA ET AL.	
	Examiner BRIAN P. YENKE	Art Unit 2622	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,046,302	05-2006	Konuma, Yasushi	348/558
*	B	US-6,781,601	08-2004	Cheung, Francis	345/629
*	C	US-6,710,817	03-2004	Oku et al.	348/569
*	D	US-6,204,887	03-2001	Hiroi, Kazushige	348/565
*	E	US-2004/0208245	10-2004	MacInnis et al.	375/240.15
*	F	US-2003/0201836	10-2003	Schoner, Brian	331/18
*	G	US-2003/0002584	01-2003	Campisano et al.	375/240.21
*	H	US-6,996,174	02-2006	Campisano et al.	375/240.13
*	I	US-6,614,441	09-2003	Jiang et al.	345/539
*	J	US-6,437,787	08-2002	Wu, Fang-Chuan	345/519
*	K	US-5,990,958	11-1999	Bheda et al.	348/407.1
*	L	US-5,760,784	06-1998	Bullis et al.	345/660
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.